

INTRODUCTION TO NEP TESTNET



Figure 1 Dashboard – Overview of the products with most failed tests.

One of the most critical elements in production is control. Can you be sure that quality is in accordance with the expectations? Error situations in produced units are expensive if not uncovered soon enough.

Test station generates a lot of different test results, stored in various ways. Reporting formats and layouts are often left to the SW engineers, consequences are that the test data is rarely used before a problem occurs. After that, it takes a lot of time and resources to gather the needed information to create reports and analysis.

Test stations can also be located worldwide, which makes the overview of production sites difficult.

NEP TestNet is an off shelf Test Data Management System that easily integrates into the test equipment on the production sites. By NEP TestNet you can reach all your production sites and test stations from your own office by the web-interface. You do not need to install any software on your own computer. By that you will have good control on how the yield and production progress is running without calling someone at production site.

You will always have the chance to down-load data (test protocol, capability numbers, yields, etc) at any time you want if you would like to do deeper analyses in your own program.

All test data will be saved locally at the test station. Test data will also automatically and frequently be uploaded to the cloud (or a central data server) when the test station is connected to internet.

You can get a login account to evaluate a demo with test-data if You are interested for further information on what the system can handle and visualize today.

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From the Dashboard you will have a picture showing a Pareto-diagram of the yield for the running products. From that you will be able to look on the progress for each product, each site or each test station. The data base is typically updated three times every hour, so the picture you will see is close to a real time picture. You can choose to view "first time yield" or "last time yield", you can also choose "All" to see if the same units is tested several times before it pass the test.



Below, are some of the views you can see by login on your account to NEP TestNet.

Figure 2. Shows the yield per month for a specific product. The choice of time interval is optional between the "Last 7 Days", "Last Month", "Last 4 Months" or "Last Year".

From a single user interface different product summaries can be produced, by clicking on suitable graph.





Once a product has been selected, options to define the parameters for the report can be used to narrow the areas of interest. This can range to a single measure point, a range of dates, a specific station and test sequence version.

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Figure 4. Single Measure point selection

Through the selection of a single test point you can obtain detailed information pertaining to that test point. This will empower test engineers to ensure test limits are suitable or if the test points require adjustments.

Scatter graphs indicating the result against the date give an excellent overview of the measure point selected.

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As well as summaries, individual reports can be taken by the use of the serial number used to identify each and every board.

Search Serial Numbers	53034032 000805 SRX E00 R09 02 2 - Passed				Tested 11 times: 2015-12-22 10:34:44 -		
Serial Number	Product SRX	Test Type Functional	Test Version 0.0.0.6	Station 91-1000	7	Operator 827	Execution Time 137.04 s
Most Recent Count: 200 -	Name	Low	High		Comp	Data	Result
53008032 000759 CCB G00 R08 04 2 F	8.17.1	0			EQ	0.000	Passed
53008032 000762 CCB G00 R08 04 2 🕞	8.1.1.1	10			LT	1.696 Ohm	Passed
53008032 000763 CCB G00 R08 04 2 🕞	8.1.1.2	10			LT	1.681 Ohm	Passed
53038032 000888 X35 F00 R18 03 2 🔳	0110	10			1.7	1.744 Ohm	Dessed
53038032 000888 X35 F00 R18 03 2	8.1.1.3	10			LI	1.744 Unm	Passed
53038032 000888 X35 F00 R18 03 2 🔳	8.1.1.4	10			LT	1.756 Ohm	Passed
53034032 000805 SRX E00 R09 02 2 P	8.1.1.5	10			LT	1.783 Ohm	Passed
53034032 000805 SRX E00 R09 02 2 E	8.1.1.6	10			LT	1.881 Ohm	Passed
53034032 000805 SRX E00 R09 02 2 📧	8.1.1.7	10			LT	1.847 Ohm	Passed
53034032 000805 SRX E00 R09 02 2 E	8.1.1.8	10			LT	1.643 Ohm	Passed
53022032 000224 IMC G00 R22 03 2 F	8.1.1.9	10			LT	1.507 Ohm	Passed
53022032 000224 IMC G00 R22 03 2 P	8.1.1.10	10			LT	1.735 Ohm	Passed
53022032 000224 IMC G00 R22 03 2 P	0 1 1 11	10			1.7	1.280 Ohm	Dessed
53022032 000224 IMC G00 R22 03 2 P	0.1.1.11	10			LI	1.360 Onm	Fassed
53022032 000224 IMC G00 R22 03 2 🔳	8.1.1.12	10			LT	1.854 Ohm	Passed
53008032 000604 CCB F00 P07 03 2 F	8.1.1.13	10			LT	1.369 Ohm	Passed
53008032 000604 CCB F00 P07 03 2 F 53008032 000604 CCB F00 P07 03 2 F	8.1.1.14	10			LT	1.479 Ohm	Passed
53022032 000224 IMC G00 R22 03 2 🕞	8.1.1.15	10			LT	1.324 Ohm	Passed
53022032 000224 IMC G00 R22 03 2 🕞	8.1.1.16	10			LT	1.305 Ohm	Passed
53022032 000224 IMC G00 R22 03 2 F 53022032 000224 IMC G00 R22 03 2 F	8.1.1.17	10			LT	1.448 Ohm	Passed

Figure 5 Test Report overview.

Overall summaries of the status and tests for each board can be displayed. From the summary individual test protocols can be selected for viewing (Figure 5).

Further, you can always export the test data from NEP TestNet to another system, tool or software if you want to do data analyze or presentation of the data differently.

For a demonstration and a personal login account to evaluate a demo with test-data, contact NEP AB.